Revision History
32K x 8 BIT HIGH SPEED CMOS SRAM

Revision	Details	Date
Rev 1.0	Initial Release	June. 2024

FEATURES

- Fast access time :15ns
- Low power consumption:
  Operating current : 80mA (5V TYP)
  40mA (3V TYP)
  Standby current : 1mA /0.5mA (5V/3V TYP)
- Wide power supply: 2.7V ~ 5.5V
- All inputs and outputs TTL compatible
- Fully static operation
- Tri-state output
- Data retention voltage : 2.0V (MIN.)
- Green package available
- Package : 28-pin 300 mil Skinny PDIP

GENERAL DESCRIPTION

The AS7C256C is a 262,144-bit high speed CMOS static random access memory organized as 32,768 words by 8 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

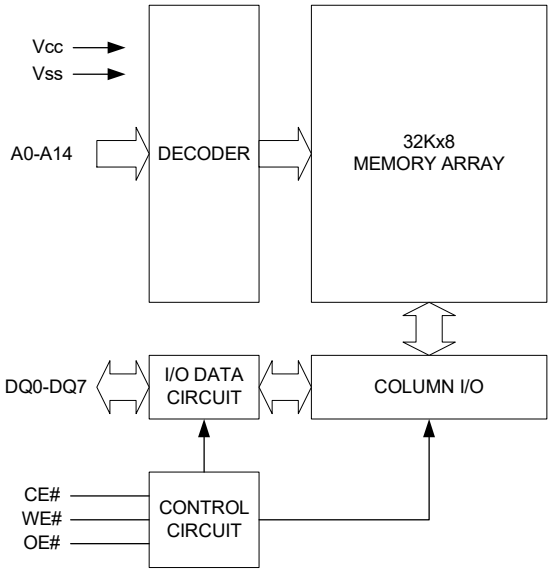
The AS7C256C is well designed for high speed system application. Easy expansion is provided by using an active LOW Chip Enable(CE#). The active LOW Write Enable(WE#) controls both writing and reading of the memory.

The AS7C256C operates from a single power supply. The range of supply voltage is from 2.7V to 5.5V and all inputs and outputs are fully TTL compatible.

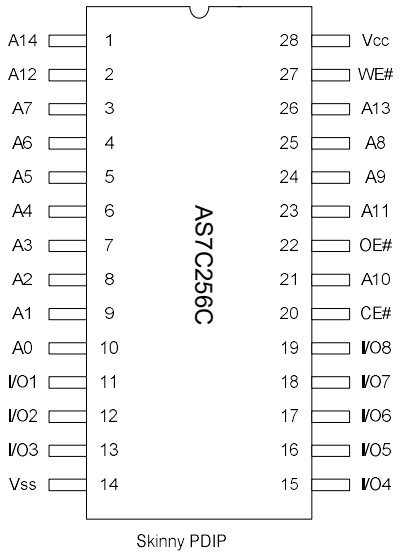
PRODUCT FAMILY

Product Family	Operating Temperature	V_{CC} Range	Speed	Power Dissipation	
				(I_{SB1},TYP.) 5V/3V	(I_{CC},TYP.) 5V(3V)
AS7C256C-15PCN	0 ~ 70℃	2.7 ~ 5.5V	15ns	2μA/1uA	80mA (40mA)

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



Skinny PDIP

PIN DESCRIPTION

SYMBOL	DESCRIPTION
A0 - A14	Address Inputs
DQ0 - DQ7	Data Inputs/Outputs
CE#	Chip Enable Input
WE#	Write Enable Input
OE#	Output Enable Input
V_{CC}	Power Supply
V_{SS}	Ground

ABSOLUTE MAXIMUN RATINGS*

PARAMETER	SYMBOL	RATING	UNIT
Voltage on V_{CC} relative to V_{SS}	V_{T1}	-0.5 to 6.5	V
Voltage on any other pin relative to V_{SS}	V_{T2}	-0.5 to V_{CC}+0.5	V
Operating Temperature	T_A	0 to 70	℃
Storage Temperature	T_{STG}	-65 to 150	℃
Power Dissipation	P_D	1	W
DC Output Current	I_{OUT}	50	mA

*Stresses greater than those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

TRUTH TABLE

MODE	CE#	OE#	WE#	I/O OPERATION	SUPPLY CURRENT
Standby	H	X	X	High-Z	I_{SB1}
Output Disable	L	H	H	High-Z	I_{CC}
Read	L	L	H	D_{OUT}	I_{CC}
Write	L	X	L	D_{IN}	I_{CC}

Note: H = V_{IH}, L = V_{IL}, X = Don't care.

DC ELECTRICAL CHARACTERISTICS

For Vcc= 2.7V~5.5V

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP. *4	MAX.	UNIT
Supply Voltage	V_{CC}		2.7	5.0	5.5	V
Input High Voltage	V_{IH}*1		2.4	-	V_{CC}+0.5	V
Input Low Voltage	V_{IL}*2		- 0.5	-	0.8	V
Input Leakage Current	I_{LI}	$V_{CC} \geqq V_{IN} \geqq V_{SS}$	- 1	-	1	µA
Output Leakage Current	I_{LO}	$V_{CC} \geqq V_{OUT} \geqq V_{SS}$, Output Disabled	- 1	-	1	µA
Output High Voltage	V_{OH}	I_{OH} = -4mA	2.4	-	-	V
Output Low Voltage	V_{OL}	I_{OL} = 8mA	-	-	0.4	V
Average Operating Power supply Current	I_{CC}	Cycle time = MIN. CE# = V_{IL} , $I_{I/O}$ = 0mA Others at V_{IL} or V_{IH}	-	80	140	mA
Standby Power Supply Current	I_{SB1}	CE# $\geqq$ V_{CC} - 0.2V, Others at 0.2V or V_{CC}-0.2V	-	1	5	mA

For Vcc= 2.7~3.6V

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP. *4	MAX.	UNIT
Supply Voltage	V_{CC}		2.7	3.3	3.6	V
Input High Voltage	V_{IH}*1		2.0	-	V_{CC}+0.5	V
Input Low Voltage	V_{IL}*2		- 0.5	-	0.6	V
Input Leakage Current	I_{LI}	$V_{CC} \geqq V_{IN} \geqq V_{SS}$	- 1	-	1	μA
Output Leakage Current	I_{LO}	$V_{CC} \geqq V_{OUT} \geqq V_{SS}$, Output Disabled	- 1	-	1	μA
Output High Voltage	V_{OH}	I_{OH} = -4mA	2.4	-	-	V
Output Low Voltage	V_{OL}	I_{OL} = 8mA	-	-	0.4	V
Average Operating Power supply Current	I_{CC}	Cycle time = MIN. CE# = V_{IL} , $I_{I/O}$ = 0mA Others at V_{IL} or V_{IH}	-	40	50	mA
Standby Power Supply Current	I_{SB1}	CE# $\geqq$ V_{CC} - 0.2V, Others at 0.2V or V_{CC}-0.2V	-	0.5	3	mA

Notes:

1. V_{IH}(max) = V_{CC} + 3.0V for pulse width less than 10ns.
2. V_{IL}(min) = V_{SS} - 3.0V for pulse width less than 10ns.
3. Over/Undershoot specifications are characterized, not 100% tested.
4. Typical values are included for reference only and are not guaranteed or tested.

Typical valued are measured at V_{CC} = $V_{CC(TYP.)}$ and T_A = 25℃

CAPACITANCE (T_A = 25℃, f = 1.0MHz)

PARAMETER	SYMBOL	MIN.	MAX.	UNIT
Input Capacitance	C_{IN}	-	6	pF
Input/Output Capacitance	$C_{I/O}$	-	8	pF

Note : These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

Input Pulse Levels	0.2V to V_{CC} - 0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	1.5V
Output Load	C_L = 30pF + 1TTL, I_{OH}/I_{OL} = -4mA/8mA

AC ELECTRICAL CHARACTERISTICS

(1) READ CYCLE

PARAMETER	SYM.	AS7C256C-15PCN		UNIT
		MIN.	MAX.	
Read Cycle Time	t_{RC}	15	-	ns
Address Access Time	t_{AA}	-	15	ns
Chip Enable Access Time	t_{ACE}	-	15	ns
Output Enable Access Time	t_{OE}	-	7	ns
Chip Enable to Output in Low-Z	t_{CLZ}*	4	-	ns
Output Enable to Output in Low-Z	t_{OLZ}*	0	-	ns
Chip Disable to Output in High-Z	t_{CHZ}*	-	7	ns
Output Disable to Output in High-Z	t_{OHZ}*	-	7	ns
Output Hold from Address Change	t_{OH}	3	-	ns

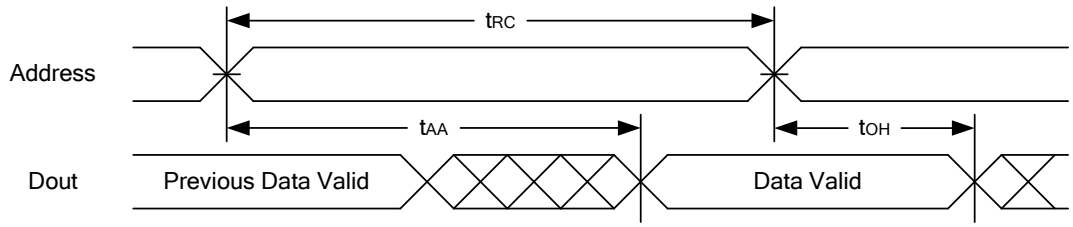
(2) WRITE CYCLE

PARAMETER	SYM.	AS7C256C-15PCN		UNIT
		MIN.	MAX.	
Write Cycle Time	t_{WC}	15	-	ns
Address Valid to End of Write	t_{AW}	12	-	ns
Chip Enable to End of Write	t_{CW}	12	-	ns
Address Set-up Time	t_{AS}	0	-	ns
Write Pulse Width	t_{WP}	10	-	ns
Write Recovery Time	t_{WR}	0	-	ns
Data to Write Time Overlap	t_{DW}	8	-	ns
Data Hold from End of Write Time	t_{DH}	0	-	ns
Output Active from End of Write	t_{OW}*	4	-	ns
Write to Output in High-Z	t_{WHZ}*	-	8	ns

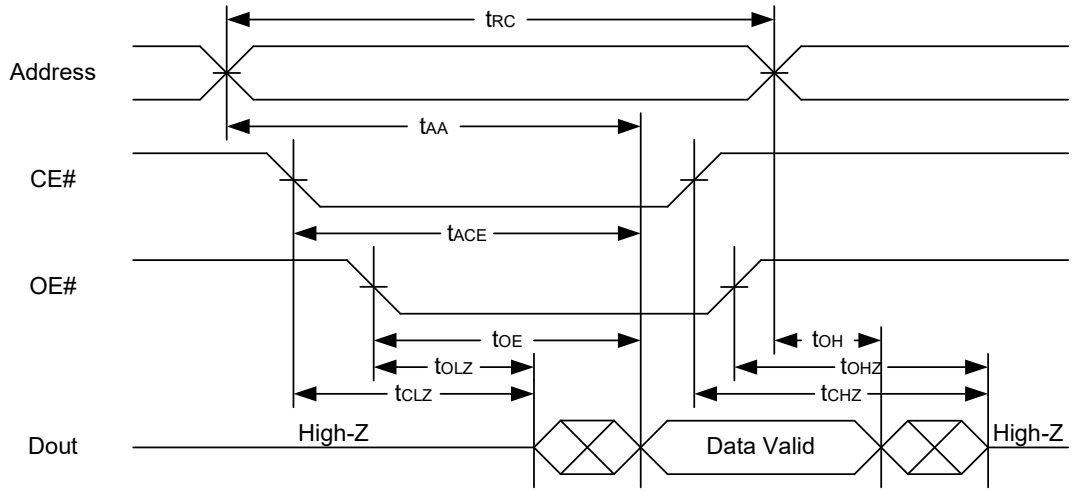
*These parameters are guaranteed by device characterization, but not production tested.

TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)

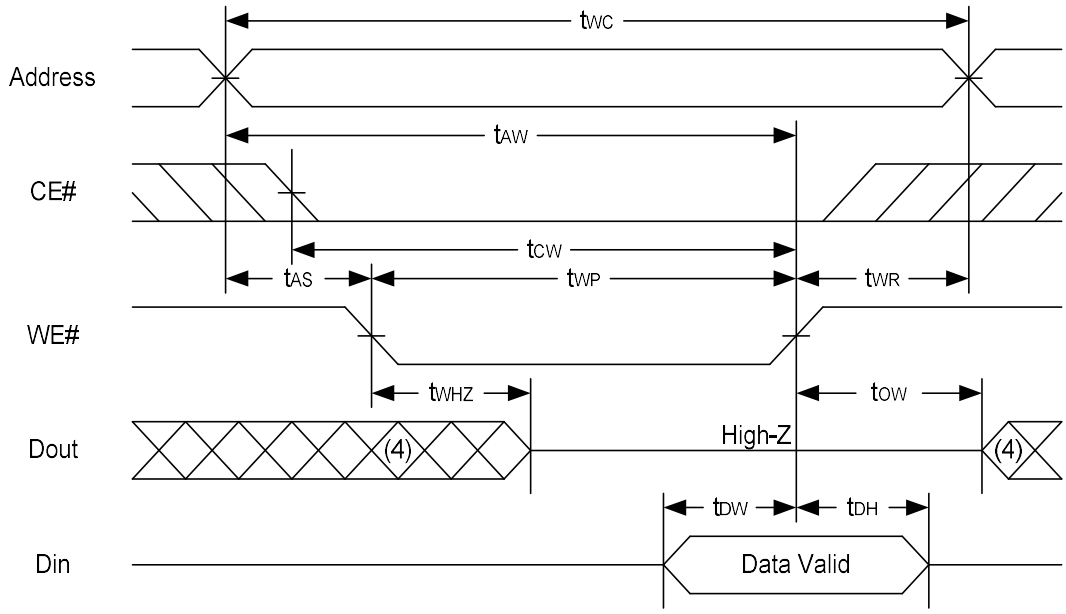


READ CYCLE 2 (CE# and OE# Controlled) (1,3,4,5)

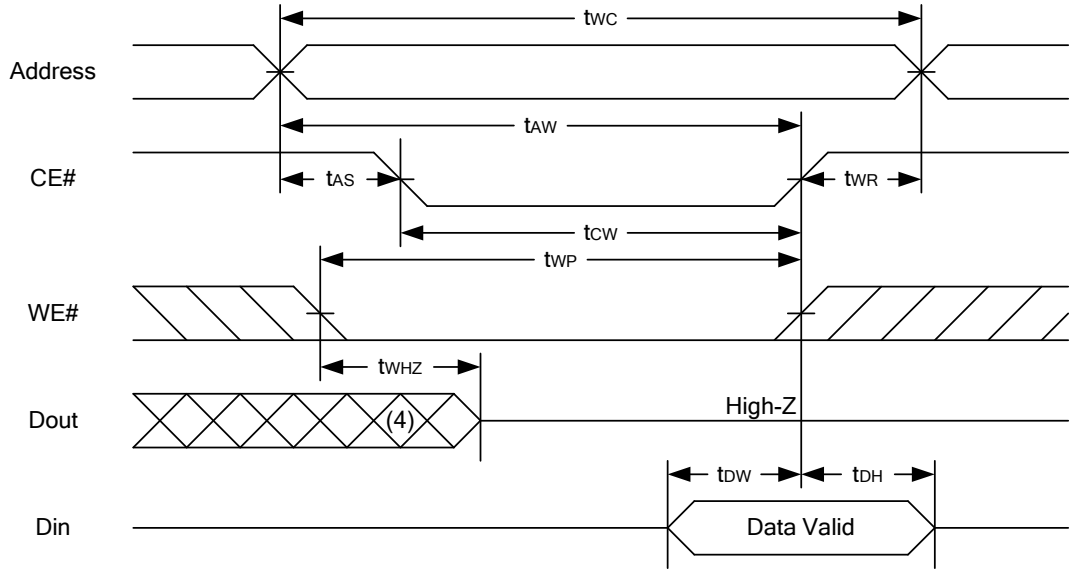


Notes :
1.WE# is high for read cycle.
2.Device is continuously selected OE# = low, CE# = low.
3.Address must be valid prior to or coincident with CE# = low.; otherwise t_{AA} is the limiting parameter.
4.t_{CLZ}, t_{OLZ}, t_{CHZ} and t_{OHZ} are specified with C_L = 5pF. Transition is measured ±500mV from steady state.
5.At any given temperature and voltage condition, t_{CHZ} is less than t_{CLZ} , t_{OHZ} is less than t_{OLZ}.

WRITE CYCLE 1 (WE# Controlled) (1,2,4,5)



WRITE CYCLE 2 (CE# Controlled) (1,4,5)



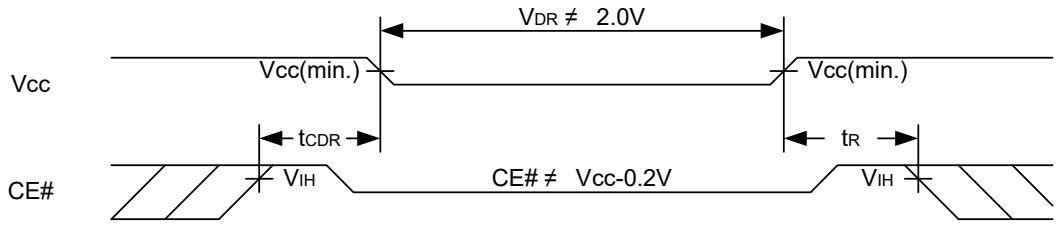
Notes :
1.A write occurs during the overlap of a low CE#, low WE#.
2.During a WE# controlled write cycle with OE# low, t_{WP} must be greater than $t_{WHZ} + t_{DW}$ to allow the drivers to turn off and data to be placed on the bus.
3.During this period, I/O pins are in the output state, and input signals must not be applied.
4.If the CE# low transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
5.t_{OW} and t_{WHZ} are specified with C_L = 5pF. Transition is measured ±500mV from steady state.

DATA RETENTION CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
V_{CC} for Data Retention	V_{DR}	CE# ≧ V_{CC} - 0.2V	2.0	-	5.5	V
Data Retention Current	I_{DR}	V_{CC} = 2.0V, CE# ≧ V_{CC} - 0.2V	-	0.3	2	mA
Chip Disable to Data Retention Time	t_{CDR}	See Data Retention Waveforms (below)	0	-	-	ns
Recovery Time	t_R		t_{RC*}	-	-	ns

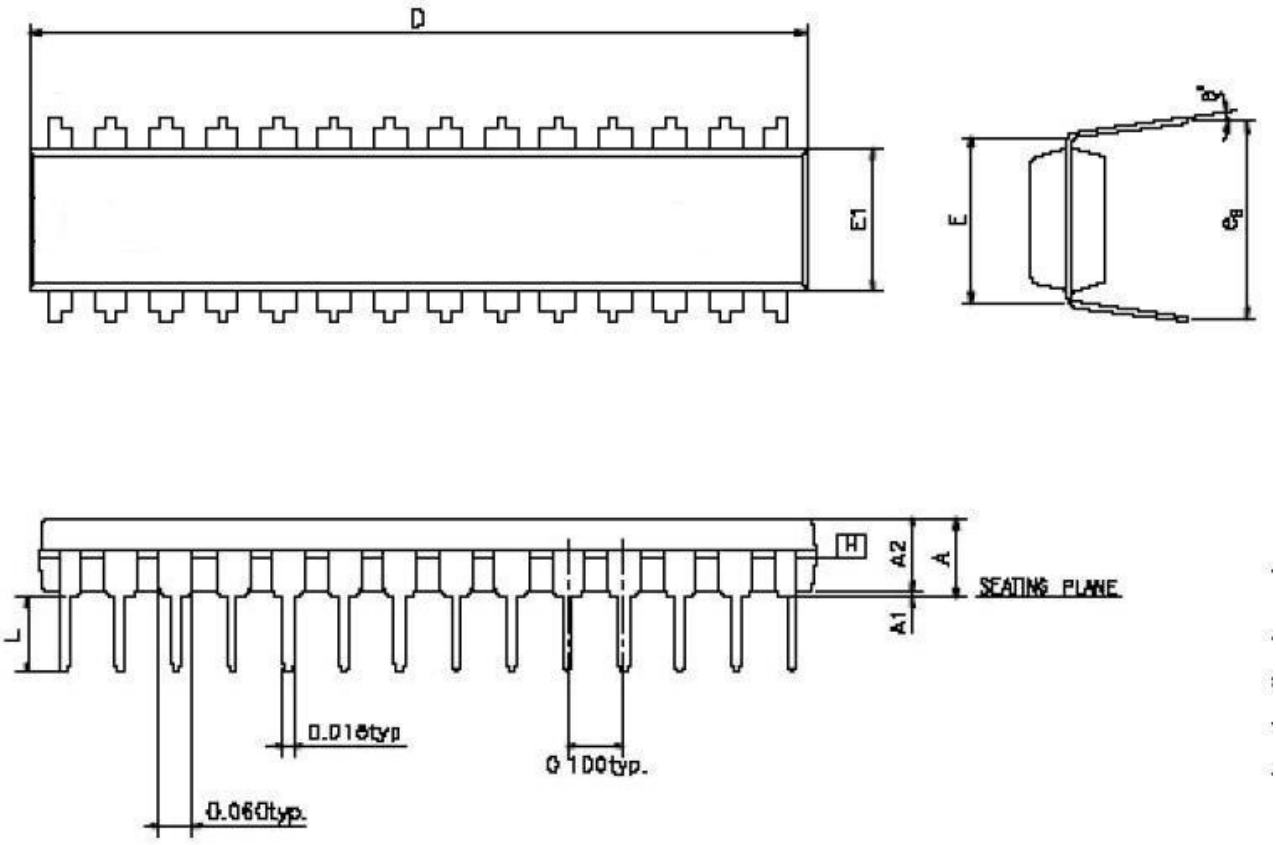
t_{RC*} = Read Cycle Time

DATA RETENTION WAVEFORM



PACKAGE OUTLINE DIMENSION

28-pin 300mil PDIP Package Outline Dimension



SYMBOLS	MIN.	NOR.	MAX.
A	–	–	0.210
A1	0.015	–	–
A2	0.125	0.130	0.135
D	1.385	1.390	1.400
E		0.310 BSC	
E1	0.283	0.288	0.293
L	0.115	0.130	0.150
e_B	0.330	0.350	0.370
θ°	0	7	15

UNIT : INCH

NOTE:

1.JEDEC OUTLINE : MS-015 AH